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- Inputs Are TTL-Voltage Compatible
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

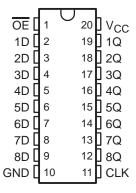
description

These 8-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

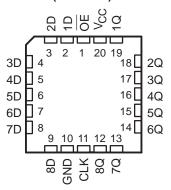
The eight flip-flops of the 'ACT574 devices are D-type edge-triggered flip-flops. On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels set up at the data (D) inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines in a bus-organized system without need for interface or pullup components.

SN54ACT574...J OR W PACKAGE SN74ACT574...DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ACT574 . . . FK PACKAGE (TOP VIEW)



OE does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT574 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ACT574 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each flip-flop)

| | INPUTS OUTF | | | | | | |
|----|-------------|---|----------------|--|--|--|--|
| OE | CLK | D | Q | | | | |
| L | \uparrow | Н | Н | | | | |
| L | \uparrow | L | L | | | | |
| L | H or L | Χ | Q ₀ | | | | |
| Н | X | Χ | Z | | | | |



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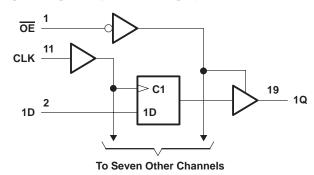
SN54ACT574, SN74ACT574 OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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logic symbol†

OE ΕN **CLK** > C1 2 19 1D 1D ∇ 1Q 3 18 2D 2Q 17 3D 3Q 16 4D 4Q 6 15 5D 5Q 14 7 6D 8 13 7D 7Q 9 12 8D 8Q

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

| Supply voltage range, V _{CC} | | –0.5 V to 7 V |
|--|--------------|---|
| Input voltage range, V _I (see Note 1) | | . –0.5 V to V_{CC} + 0.5 V |
| Output voltage range, VO (see Note 1) | | . -0.5 V to V _{CC} + 0.5 V |
| Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$). | | ±20 mA |
| Output clamp current, IOK (VO < 0 or VO > VCO | C) | ±20 mA |
| Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$ | | |
| Continuous current through V _{CC} or GND | | ±200 mA |
| Package thermal impedance, θ _{JA} (see Note 2) | : DB package | 70°C/W |
| - | DW package | 58°C/W |
| | N package | 69°C/W |
| | PW package | 83°C/W |
| Storage temperature range, T _{stq} | | –65°C to 150°C |

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The package thermal impedance is calculated in accordance with JESD 51.



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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recommended operating conditions (see Note 3)

| | | SN54ACT574 | | SN74ACT574 | | UNIT |
|----------------|------------------------------------|------------|-----|------------|-----|------|
| | | MIN | MAX | MIN | MAX | UNIT |
| Vcc | Supply voltage | 4.5 | 5.5 | 4.5 | 5.5 | V |
| VIH | High-level input voltage | 2 | 7 | 2 | | V |
| VIL | Low-level input voltage | | 0.8 | | 0.8 | V |
| ٧ _I | Input voltage | 0 | Vcc | 0 | VCC | V |
| ٧o | Output voltage | 0 | Vcc | 0 | VCC | V |
| IOH | High-level output current | 2 | -24 | | -24 | mA |
| loL | Low-level output current | 30/ | 24 | | 24 | mA |
| Δt/Δν | Input transition rise or fall rate | 0 | 8 | 0 | 8 | ns/V |
| TA | Operating free-air temperature | -55 | 125 | -40 | 85 | °C |

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| DADAMETED | TEST CONDITIONS | vcc | T _A = 25°C | | | SN54A | CT574 | SN74ACT574 | | LINIT | |
|-----------|---|-------|-----------------------|------|-------|---------------------------------------|-------|------------|------|-------|--|
| PARAMETER | TEST CONDITIONS | | MIN | TYP | MAX | MIN | MAX | MIN | MAX | UNIT | |
| | I _{OH} = -50 μA | 4.5 V | 4.4 | 4.49 | | 4.4 | | 4.4 | | | |
| | | 5.5 V | 5.4 | 5.49 | | 5.4 | | 5.4 | | | |
| \/o., | I _{OH} = -24 mA | 4.5 V | 3.86 | | | 3.7 | | 3.76 | | V | |
| Voн | 10H = -24 IIIA | 5.5 V | 4.86 | | | 4.7 | | 4.76 | | V | |
| | $I_{OH} = -50 \text{ mA}^{\dagger}$ | 5.5 V | | | | 3.85 | | | | 1 | |
| | $I_{OH} = -75 \text{ mA}^{\dagger}$ | 5.5 V | | | | | 7 | 3.85 | | | |
| | I _{OL} = 50 μA | 4.5 V | | | 0.1 | | 0.1 | | 0.1 | V | |
| | | 5.5 V | | | 0.1 | | 0.1 | | 0.1 | | |
| \/a. | I _{OL} = 24 mA | 4.5 V | | | 0.36 | 7 | 0.44 | | 0.44 | | |
| VOL | | 5.5 V | | | 0.36 | $\mathcal{O}_{\mathcal{I}_{\lambda}}$ | 0.44 | | 0.44 | | |
| | I _{OL} = 50 mA [†] | 5.5 V | | | | 70, | 1.65 | | | | |
| | $I_{OL} = 75 \text{ mA}^{\dagger}$ | 5.5 V | | | | 10 | | | 1.65 | | |
| loz | $V_O = V_{CC}$ or GND | 5.5 V | | | ±0.25 | | ±5 | | ±2.5 | μΑ | |
| lį | $V_I = V_{CC}$ or GND | 5.5 V | | | ±0.1 | | ±1 | | ±1 | μΑ | |
| Icc | $V_I = V_{CC}$ or GND, $I_O = 0$ | 5.5 V | | | 4 | | 80 | | 40 | μΑ | |
| Δlcc‡ | One input at 3.4 V, Other inputs at GND or V _{CC} | 5.5 V | | 0.6 | | | 1.5 | | 1.5 | mA | |
| Ci | $V_I = V_{CC}$ or GND | 5 V | | 4.5 | | | | | | pF | |

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

| | | T _A = 25°C | | T _A = 25°C SN54ACT574 | | SN74ACT574 | | UNIT |
|-----------------|---------------------------------|-----------------------|-----|----------------------------------|-----|------------|-----|------|
| | | | MAX | MIN | MAX | MIN | MAX | UNIT |
| t _W | Pulse duration, CLK high or low | 3 | | 5 | 100 | 4 | | ns |
| t _{su} | Setup time, data before CLK↑ | 2.5 | | 3.5 | 116 | 2.5 | | ns |
| t _h | Hold time, data after CLK↑ | 1 | | 2 | | 1 | | ns |



[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

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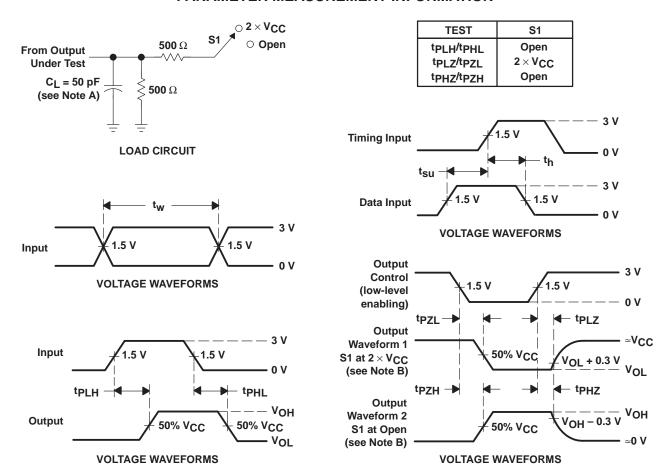
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5V (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM | то | T _A = 25°C | | | SN54ACT574 | | SN74ACT574 | | UNIT |
|------------------|-------------------|---------------|-----------------------|-----|------|------------|------|------------|------|------|
| PARAMETER | PARAMETER (INPUT) | | MIN | TYP | MAX | MIN | MAX | MIN | MAX | UNIT |
| f _{max} | | | 100 | 110 | | 70 | 12. | 85 | | MHz |
| ^t PLH | CLK | Q | 2.5 | 7 | 11 | 1.5 | 13.5 | 2 | 12 | ns |
| ^t PHL | | | 2 | 6.5 | 10 | 1.5 | 12.5 | 1.5 | 11 | 110 |
| ^t PZH | | Q | 2 | 6.4 | 9.5 | 1.5 | 11 | 1.5 | 10 | 20 |
| ^t PZL | ŌĒ | ά | 2 | 6 | 9 | 1.5 | 11 | 1.5 | 10 | ns |
| ^t PHZ | ŌĒ | 0. | 2 | 7 | 10.5 | 01.5 | 12 | 1.5 | 11.5 | no |
| t _{PLZ} | OE . | Q | 2 | 5.5 | 8.5 | 1.5 | 10 | 1.5 | 9 | ns |

operating characteristics, V_{CC} = 5 V, T_A = 25°C

| PARAMETER | | TEST CO | TYP | UNIT | |
|-----------------|-------------------------------|------------------------|-----------|------|----|
| C _{pd} | Power dissipation capacitance | $C_L = 50 \text{ pF},$ | f = 1 MHz | 40 | pF |

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \ \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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